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Docket No.: 06920/000J924-US0  
(PATENT)

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:  
Hiroshi Koshiba

Application No.: 09/975,835

Confirmation No.: 2278

Filed: October 11, 2001

Art Unit: 2133

For: SEMICONDUCTOR TEST APPARATUS AND  
CONTROL METHOD THEREFOR

Examiner: J. P. Trimmings

### AMENDMENT AFTER FINAL ACTION (37 C.F.R. SECTION 1.116)

MS AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

### INTRODUCTORY COMMENTS

In response to the Office Action dated December 3, 2004 (Paper No. 11232004), and subject to the approval of the Examiner, please amend the above-identified U.S. patent application as follows:

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Amendments to the Drawings** begin on page 6 of this paper and include an attached replacement sheet.

**Remarks/Arguments** begin on page 7 of this paper.

An **Appendix** including amended drawing figures is attached following page 10 of this paper.

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